

## **Dr Kim Caneiro**

Kim obtained his M.Sc in electrical engineering in 1970 from the Technical University of Denmark, specialising in physics. Upon finishing his military service, he continued with a Ph.D studies in neutron scattering from condensed matter from the Copenhagen University. He served as a Lecturer with them until 1986. He spent his postdoctoral period in Brookhaven National Laboratory, and later spent his sabbaticals as a visiting scientist in Europe and overseas. Kim has published more than 100 scientific papers and monographs, with major contributions within the field of synthetic metals.

In 1986 Kim undertook the challenge of starting a modern national metrology institute, Danish Fundamental Metrology Ltd (DFM). DFM was one of the first metrology institutes to apply scanning microscopy for metrology. Kim has served as a chairman of EUROMET and subsequently as President of euspen, of which he is a founding member. Kim is currently a member of the Comité International des Poids et Mesures.

Areas of interest within euspen include metrology, nanotechnology, scanning probe microscopy, optical diffraction microscopy, and innovation.